

54AC/74AC139 • 54ACT/74ACT139 Dual 1-of-4 Decoder/Demultiplexer

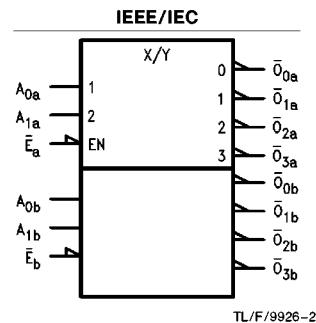
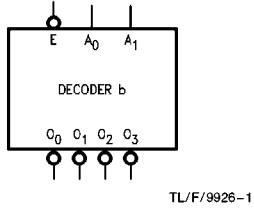
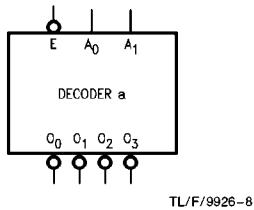
General Description

The 'AC/'ACT139 is a high-speed, dual 1-of-4 decoder/demultiplexer. The device has two independent decoders, each accepting two inputs and providing four mutually-exclusive active-LOW outputs. Each decoder has an active-LOW Enable input which can be used as a data input for a 4-output demultiplexer. Each half of the 'AC/'ACT139 can be used as a function generator providing all four minterms of two variables.

Features

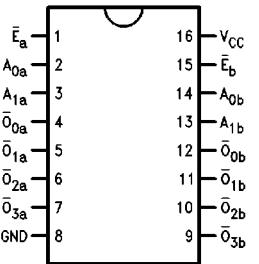
- I_{CC} reduced by 50%
- Multifunction capability
- Two completely independent 1-of-4 decoders
- Active LOW mutually exclusive outputs
- Outputs source/sink 24 mA
- 'ACT139 has TTL-compatible inputs
- Standard Military Drawing (SMD)
 - 'AC139: 5962-87623
 - 'ACT139: 5962-87553

Logic Symbols



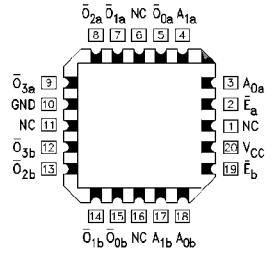
Connection Diagrams

Pin Assignment
for DIP, Flatpak and SOIC



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Pin Assignment
for LCC

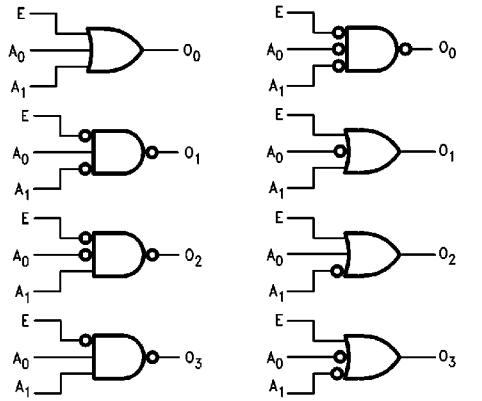


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Functional Description

The 'AC/'ACT139 is a high-speed dual 1-of-4 decoder/demultiplexer. The device has two independent decoders, each of which accepts two binary weighted inputs (A_0-A_1) and provides four mutually exclusive active-LOW outputs ($\bar{O}_0-\bar{O}_3$). Each decoder has an active-LOW enable (E). When E is HIGH all outputs are forced HIGH. The enable can be used as the data input for a 4-output demultiplexer application. Each half of the 'AC/'ACT139 generates all four minterms of two variables. These four minterms are useful in some applications, replacing multiple gate functions as shown in *Figure a*, and thereby reducing the number of packages required in a logic network.



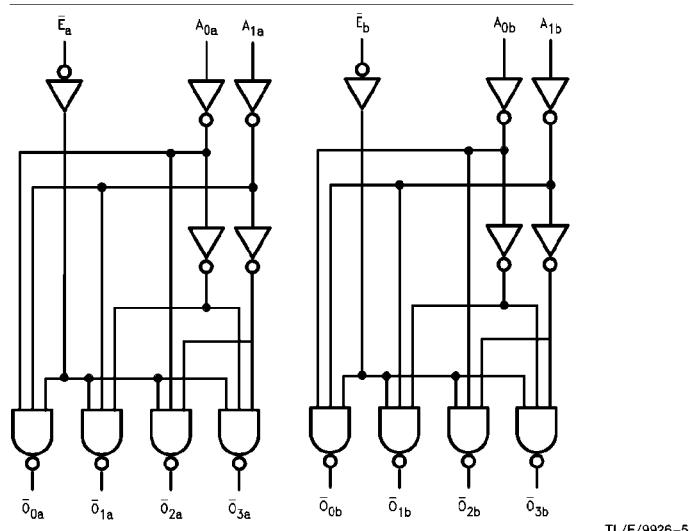
Truth Table

E	Inputs		Outputs			
	A_0	A_1	\bar{O}_0	\bar{O}_1	\bar{O}_2	\bar{O}_3
H	X	X	H	H	H	H
L	L	L	L	H	H	H
L	H	L	H	L	H	H
L	L	H	H	H	L	H
L	H	H	H	H	H	L

H = HIGH Voltage Level
L = LOW Voltage Level
X = Immortal

FIGURE a. Gate Functions (Each Half)

Logic Diagram



TL/F/9926-5

Please note that this diagram is provided only for the understanding of logic operations and should not be used to estimate propagation delays.

Absolute Maximum Rating (Note 1)

If Military/Aerospace specified devices are required, please contact the National Semiconductor Sales Office/Distributors for availability and specifications.

Supply Voltage (V_{CC})	$-0.5V$ to $+7.0V$
DC Input Diode Current (I_{IK})	
$V_I = -0.5V$	-20 mA
$V_I = V_{CC} + 0.5V$	$+20\text{ mA}$
DC Input Voltage (V_I)	$-0.5V$ to $V_{CC} + 0.5V$
DC Output Diode Current (I_{OK})	
$V_O = -0.5V$	-20 mA
$V_O = V_{CC} + 0.5V$	$+20\text{ mA}$
DC Output Voltage (V_O)	$-0.5V$ to $V_{CC} + 0.5V$
DC Output Source or Sink Current (I_O)	$\pm 50\text{ mA}$
DC V_{CC} or Ground Current per Output Pin (I_{CC} or I_{GND})	$\pm 50\text{ mA}$
Storage Temperature (T_{STG})	-65°C to $+150^{\circ}\text{C}$
Junction Temperature (T_J)	
CDIP	175°C
PDIP	140°C

Note 1: Absolute maximum ratings are those values beyond which damage to the device may occur. The databook specifications should be met, without exception, to ensure that the system design is reliable over its power supply, temperature, and output/input loading variables. National does not recommend operation of FACT™ circuits outside databook specifications.

Recommended Operating Conditions

Supply Voltage (V_{CC})	$2.0V$ to $6.0V$
'AC	$4.5V$ to $5.5V$
'ACT	
Input Voltage (V_I)	$0V$ to V_{CC}
Output Voltage (V_O)	$0V$ to V_{CC}
Operating Temperature (T_A)	
74AC/ACT	-40°C to $+85^{\circ}\text{C}$
54AC/ACT	-55°C to $+125^{\circ}\text{C}$
Minimum Input Edge Rate ($\Delta V/\Delta t$)	
'AC Devices	
V_{IN} from 30% to 70% of V_{CC}	
V_{CC} @ $3.3V, 4.5V, 5.5V$	
'ACT Devices	125 mV/ns
V_{IN} from $0.8V$ to $2.0V$	
V_{CC} @ $4.5V, 5.5V$	
Minimum Input Edge Rate ($\Delta V/\Delta t$)	125 mV/ns

DC Characteristics for 'AC Family Devices

Symbol	Parameter	V_{CC} (V)	74AC		54AC	74AC	Units	Conditions
			$T_A = +25^{\circ}\text{C}$		$T_A = -55^{\circ}\text{C}$ to $+125^{\circ}\text{C}$	$T_A = -40^{\circ}\text{C}$ to $+85^{\circ}\text{C}$		
			Typ	Guaranteed Limits				
V_{IH}	Minimum High Level Input Voltage	3.0 4.5 5.5	1.5 2.25 2.75	2.1 3.15 3.85	2.1 3.15 3.85	2.1 3.15 3.85	V	$V_{OUT} = 0.1V$ or $V_{CC} - 0.1V$
V_{IL}	Maximum Low Level Input Voltage	3.0 4.5 5.5	1.5 2.25 2.75	0.9 1.35 1.65	0.9 1.35 1.65	0.9 1.35 1.65	V	$V_{OUT} = 0.1V$ or $V_{CC} - 0.1V$
V_{OH}	Minimum High Level Output Voltage	3.0 4.5 5.5	2.99 4.49 5.49	2.9 4.4 5.4	2.9 4.4 5.4	2.9 4.4 5.4	V	$I_{OUT} = -50\text{ }\mu\text{A}$
		3.0 4.5 5.5		2.56 3.86 4.86	2.4 3.7 4.7	2.46 3.76 4.76	V	* $V_{IN} = V_{IL}$ or V_{IH} -12 mA $I_{OH} = -24\text{ mA}$ -24 mA
V_{OL}	Maximum Low Level Output Voltage	3.0 4.5 5.5	0.002 0.001 0.001	0.1 0.1 0.1	0.1 0.1 0.1	0.1 0.1 0.1	V	$I_{OUT} = 50\text{ }\mu\text{A}$
		3.0 4.5 5.5		0.36 0.36 0.36	0.50 0.50 0.50	0.44 0.44 0.44	V	* $V_{IN} = V_{IL}$ or V_{IH} 12 mA $I_{OL} = 24\text{ mA}$ 24 mA

*All outputs loaded; thresholds on input associated with output under test.

DC Characteristics for 'AC Family Devices (Continued)

Symbol	Parameter	V _{CC} (V)	74AC		54AC	74AC	Units	Conditions
			T _A = + 25°C		T _A = - 55°C to + 125°C	T _A = - 40°C to + 85°C		
			Typ	Guaranteed Limits				
I _{IN}	Maximum Input Leakage Current	5.5		± 0.1	± 1.0	± 1.0	μA	V _I = V _{CC} , GND
I _{OLD}	†Minimum Dynamic Output Current	5.5			50	75	mA	V _{OLD} = 1.65V Max
I _{OHD}		5.5			- 50	- 75	mA	V _{OHD} = 3.85V Min
I _{CC}	Maximum Quiescent Supply Current	5.5		4.0	80.0	40.0	μA	V _{IN} = V _{CC} or GND

†Maximum test duration 2.0 ms, one output loaded at a time.

Note: I_{IN} and I_{CC} @ 3.0V are guaranteed to be less than or equal to the respective limit @ 5.5V V_{CC}.

I_{CC} for 54AC @ 25°C is identical to 74AC @ 25°C.

DC Characteristics for 'ACT Family Devices

Symbol	Parameter	V _{CC} (V)	74ACT		54ACT	74ACT	Units	Conditions
			T _A = + 25°C		T _A = - 55°C to + 125°C	T _A = - 40°C to + 85°C		
			Typ	Guaranteed Limits				
V _{IH}	Minimum High Level Input Voltage	4.5 5.5	1.5 1.5	2.0 2.0	2.0 2.0	2.0 2.0	V	V _{OUT} = 0.1V or V _{CC} - 0.1V
V _{IL}	Maximum Low Level Input Voltage	4.5 5.5	1.5 1.5	0.8 0.8	0.8 0.8	0.8 0.8	V	V _{OUT} = 0.1V or V _{CC} - 0.1V
V _{OH}	Minimum High Level Output Voltage	4.5 5.5	4.49 5.49	4.4 5.4	4.4 5.4	4.4 5.4	V	I _{OUT} = - 50 μA
		4.5 5.5		3.86 4.86	3.70 4.70	3.76 4.76	V	*V _{IN} = V _{IL} or V _{IH} I _{OH} - 24 mA
V _{OL}	Maximum Low Level Output Voltage	4.5 5.5	0.001 0.001	0.1 0.1	0.1 0.1	0.1 0.1	V	I _{OUT} = 50 μA
		4.5 5.5		0.36 0.36	0.50 0.50	0.44 0.44	V	*V _{IN} = V _{IL} or V _{IH} I _{OL} 24 mA
I _{IN}	Maximum Input Leakage Current	5.5		± 0.1	± 1.0	± 1.0	μA	V _I = V _{CC} , GND
I _{CCT}	Maximum I _{CC} /Input	5.5	0.6		1.6	1.5	mA	V _I = V _{CC} - 2.1V
I _{OLD}	†Minimum Dynamic Output Current	5.5			50	75	mA	V _{OLD} = 1.65V Max
I _{OHD}		5.5			- 50	- 75	mA	V _{OHD} = 3.85V Min
I _{CC}	Maximum Quiescent Supply Current	5.5		4.0	80.0	40.0	μA	V _{IN} = V _{CC} or GND

*All outputs loaded; thresholds on input associated with output under test.

†Maximum test duration 2.0 ms, one output loaded at a time.

Note: I_{CC} for 54ACT @ 25°C is identical to 74ACT @ 25°C.

AC Electrical Characteristics

Symbol	Parameter	V _{CC} * (V)	74AC			54AC		74AC		Units	
			T _A = +25°C C _L = 50 pF			T _A = -55°C to +125°C C _L = 50 pF		T _A = -40°C to +85°C C _L = 50 pF			
			Min	Typ	Max	Min	Max	Min	Max		
t _{PLH}	Propagation Delay A _n to \bar{O}_n	3.3 5.0	4.0 3.0	8.0 6.5	11.5 8.5	1.0 1.0	14.5 11.0	3.5 2.5	13.0 9.5	ns	
t _{PHL}	Propagation Delay A _n to \bar{O}_n	3.3 5.0	3.0 2.5	7.0 5.5	10.0 7.5	1.0 1.0	12.5 10.0	2.5 2.0	11.0 8.5	ns	
t _{PLH}	Propagation Delay \bar{E}_n to \bar{O}_n	3.3 5.0	4.5 3.5	9.5 7.0	12.0 8.5	1.0 1.0	14.5 11.0	3.5 3.0	13.0 10.0	ns	
t _{PHL}	Propagation Delay \bar{E}_n to \bar{O}_n	3.3 5.0	4.0 2.5	8.0 6.0	10.0 7.5	1.0 1.0	12.5 10.0	3.0 2.5	11.0 8.5	ns	

*Voltage Range 3.3 is 3.3V ± 0.3V
Voltage Range 5.0 is 5.0V ± 0.5V

AC Electrical Characteristics

Symbol	Parameter	V _{CC} * (V)	74ACT			54ACT		74ACT		Units	
			T _A = +25°C C _L = 50 pF			T _A = -55°C to +125°C C _L = 50 pF		T _A = -40°C to +85°C C _L = 50 pF			
			Min	Typ	Max	Min	Max	Min	Max		
t _{PLH}	Propagation Delay A _n to \bar{O}_n	5.0	1.5	6.0	8.5	1.0	12.0	1.5	9.5	ns	
t _{PHL}	Propagation Delay A _n to \bar{O}_n	5.0	1.5	6.0	9.5	1.0	11.0	1.5	10.5	ns	
t _{PLH}	Propagation Delay \bar{E}_n to \bar{O}_n	5.0	2.5	7.0	10.0	1.0	12.5	2.0	11.0	ns	
t _{PHL}	Propagation Delay \bar{E}_n to \bar{O}_n	5.0	2.0	7.0	9.5	1.0	12.0	1.5	10.5	ns	

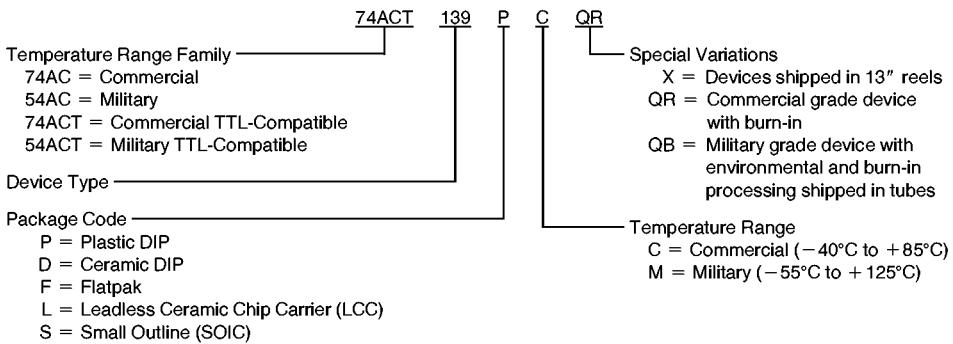
*Voltage Range 5.0 is 5.0V ± 0.5V

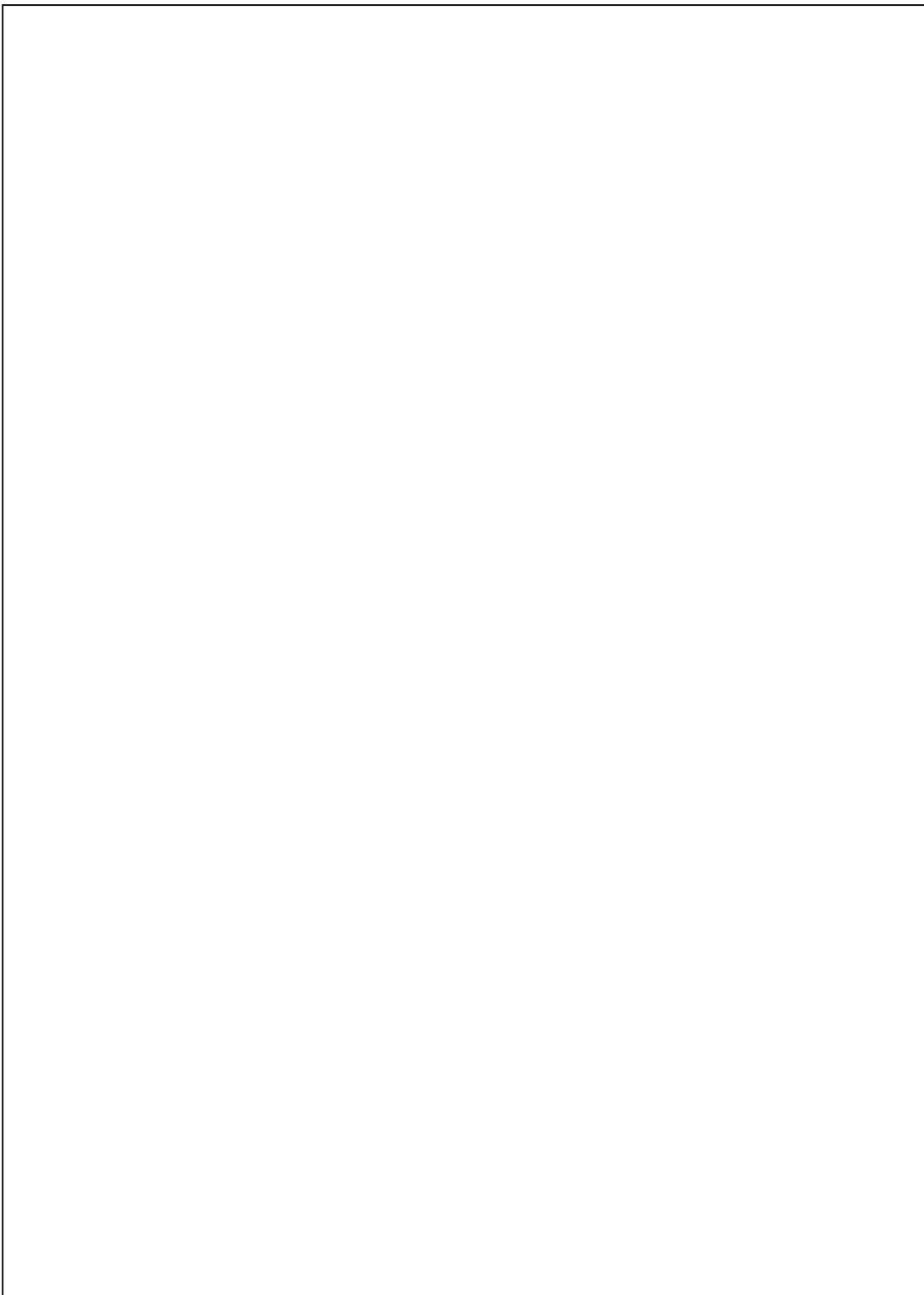
Capacitance

Symbol	Parameter	Typ	Units	Conditions
C _{IN}	Input Capacitance	4.5	pF	V _{CC} = OPEN
C _{PD}	Power Dissipation Capacitance	40.0	pF	V _{CC} = 5.0V

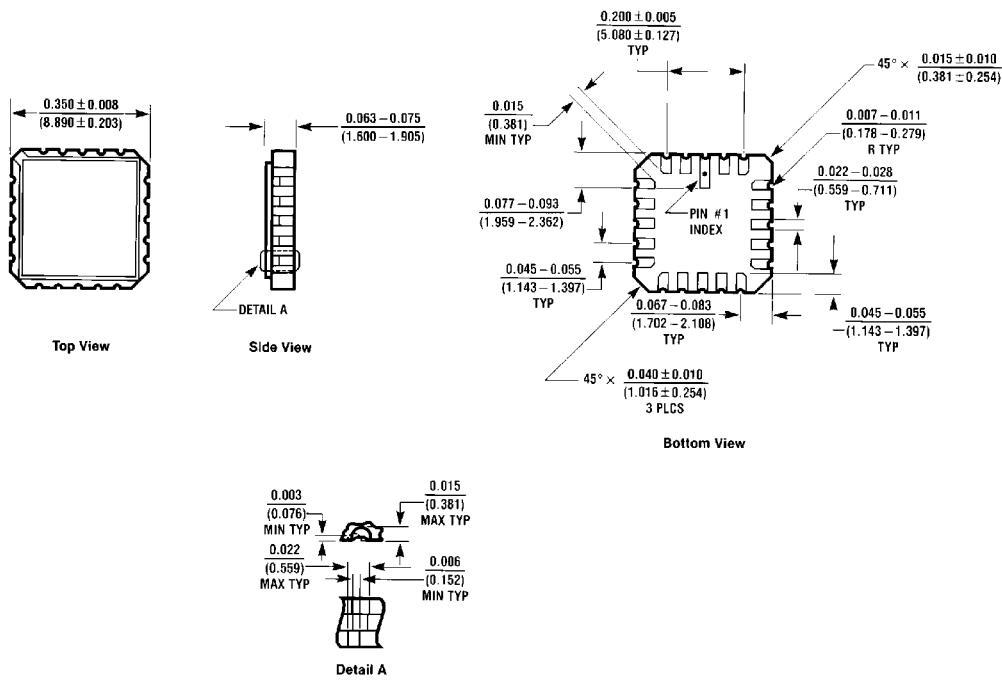
Ordering Information

The device number is used to form part of a simplified purchasing code where the package type and temperature range are defined as follows:



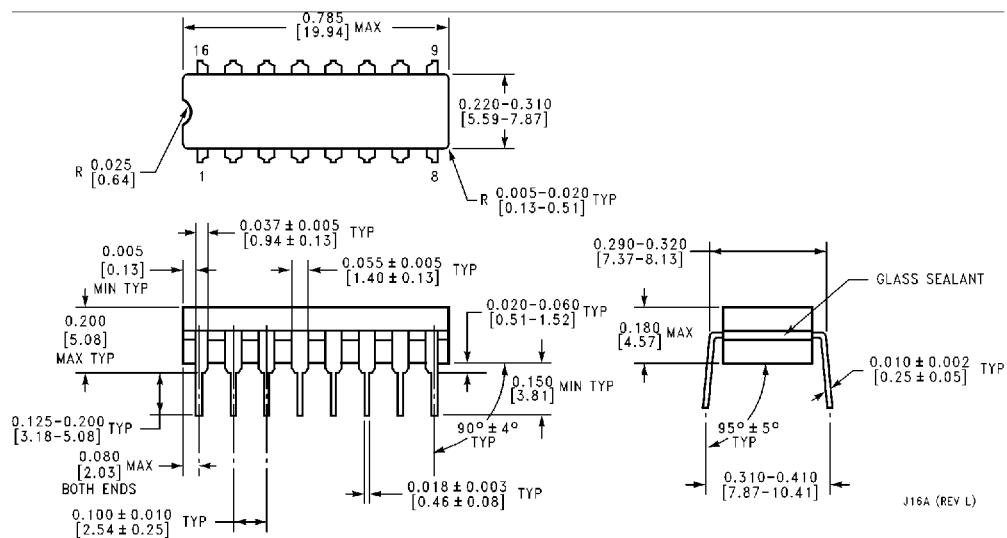


Physical Dimensions inches (millimeters)



20 Terminal Ceramic Leadless Chip Carrier (L)
NS Package Number E20A

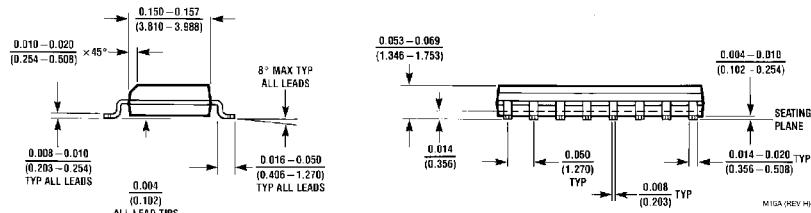
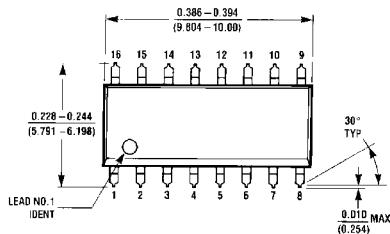
E20A (REV D)



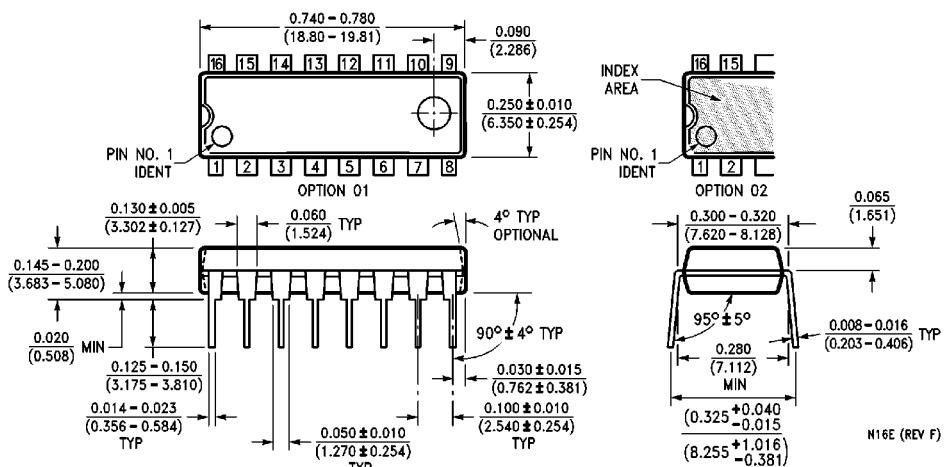
16 Lead Ceramic Dual In-Line Package (D)
NS Package Number J16A

J16A (REV L)

Physical Dimensions inches (millimeters) (Continued)

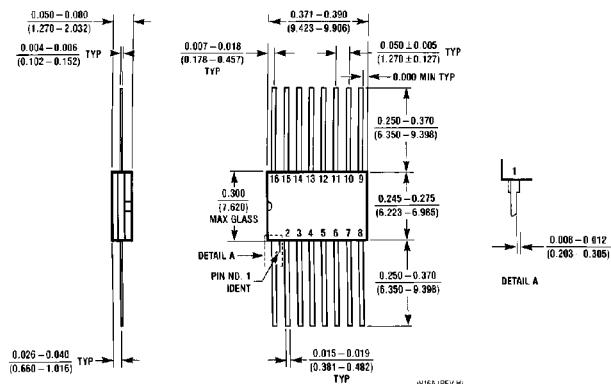


**16 Lead Small Outline Integrated Circuit (S)
NS Package Number M16A**



**16 Lead Plastic Dual-In-Line Package (P)
NS Package Number N16E**

Physical Dimensions inches (millimeters) (Continued)



**16 Lead Ceramic Flatpak (F)
NS Package Number W16A**

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2. A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.



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